

<b>Notice of References Cited</b>	Application/Control No. <b>10/008,670</b>	Applicant(s)/Patent Under Reexam <b>TSONTZIDIS et al</b>	
	Examiner <b>Philip H. Leung</b>	Art Unit <b>3742</b>	Page 1 of 1

**U.S. PATENT DOCUMENTS**

		Document Number <small>Country Code-Number-Kind Code</small>	Date <small>MM-YYYY<sup>1</sup></small>	Name	Classification <sup>2</sup>	
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	B	5,217,768	6/1993	Walters et al	426	234
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**NON-PATENT DOCUMENTS**

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